

850 nm 2.5 G GaAs PIN Die

PL-DD0-00-S30-C0



Key Features

- Topside connections for both contacts
- Large topside detection area
- Anti-reflective coating for 850 nm
- Monolithic insulating mounting surface
- Data rates from 622 Mbps to 2.5 Gbps
- Custom physical configuration and performance specification tolerances are available

Benefits

- Large active area provides improved alignment tolerances and ease of barrel attachment
- Small die dimensions allow flexible assembly options

The JDSU single die 850 nm 2.5 Gbps GaAs PIN is designed for high-speed optical data communication applications. The topside illuminated device has a large optical detection area, $\text{Ø}=120\ \mu\text{m}$, for increased process tolerance during assembly. The backside mounting surface is electrically isolated from the device electrodes for simplified assembly. The PIN is designed for datacom applications using 850 nm multi-mode 50/125 μm or 62.5/125 μm fiber.

Electro-optical Characteristics

 (T_{case} = 30 °C, CW operation unless otherwise stated.)

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
PIN Diode						
Detection wavelength	λ_p			850		nm
Operating temperature	T _{op}		-40		85	°C
Detection aperture	D			120		μm
Responsivity	R	V _R = 1.6 V λ = 850 nm	0.55	0.6		A/W
Dark current	I _D	V _R = 1.6 V		0.1	1.0	nA
Breakdown voltage	V _B		40			V
Capacitance	C	V _R = 2.0 V f = 1 MHz	0.6	0.75	0.8	pF
Rise/Fall time ¹	t _r t _f	20% - 80% 20% - 80%		100		psec
Bandwidth	BW	V _R = 2.0 V		3		GHz

1. Packaging, coupling, electronics and optical measurement hardware affect rise/fall time measurement.

Order Information

For more information on this or other products and their availability, please contact your local JDSU account manager or JDSU directly at 1-800-498-JDSU (5378) in North America and +800-5378-JDSU worldwide or via e-mail at customer.service@jdsu.com.

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Part Number	Description
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